

# Search Notes



Application/Control No.

10/656,835

Examiner

Yon Couso

Applicant(s)/Patent under  
Reexamination

CHO ET AL.

Art Unit

2624

## SEARCHED

Class	Subclass	Date	Examiner
382	274		
	270		
	254		
	162		
	167		
358	1.9	10-19-06 <i>ym</i>	
	3.27		
	3.26		
	518		
345	600		
	617		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PG pub	searched		
interference	search		
	included	10-19-06	
			<i>ym</i>

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East searched		
IEEE author searched	10-19-06 <i>ym</i>	
PATM inventor searched		